

Notice of References Cited		Application/Control No. 10/047,280	Applicant(s)/Patent Under Reexamination YIP ET AL.	
		Examiner Tanh Q. Nguyen	Art Unit 2182	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0003790 A1	01-2003	Cuevas, Peter	439/266
	B	US-			
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	D	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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